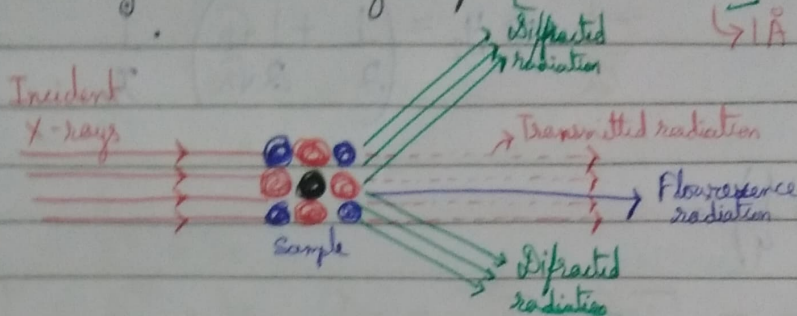


XPD - X-Ray Diffraction

An X-ray has wavelength of $[0.1 - 100 \text{ \AA}]$ range
 $\rightarrow 1 \text{ \AA} = 0.1 \text{ nanometres}$



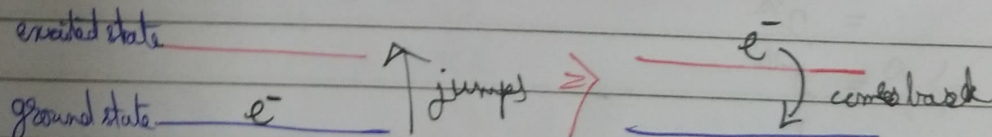
Samples \rightarrow crystalline solid

Here, the Sample will absorb \neq "some radiation"

Here: $\text{Absorbed radiation} = \text{Incident Radiation} - \text{Transmitted Radiation}$
 \rightarrow Absorbed radiation

• Diffracted radiation: Radiation deflected by sample after X-rays are incident on the sample.
This diffraction depends on atoms present in sample.

• Fluorescence radiation: When the incident radiation goes through the sample, then some atoms will absorb this radiation.



The electrons of those atoms will go to excited state when the electrons come down to ground state.

\Downarrow
Radiation will be emitted as a result

This emitted radiation is called Fluorescence radiation.

XRD methods rely on scattering of X-rays by crystals
Use cases / Application:-

- 1) I identify crystal structure of any solid sample
- 2) Analyze physical properties (like crystal size, orientation etc)
- 3) Measure purity of the sample

XRD suggested by

X-Ray Diffraction was proven by Bragg

→ He stated that X-ray dif scattering can be considered as reflection from successive planes of atoms (in the crystal/sample)

→ However, unlike reflection of ordinary light
Reflection of X-rays can only take place at "certain angle"

② This certain angle is determined by the }
① wavelength (λ) of X-ray and

② Distance of the plane inside the crystal }

This relation between:- ① Wavelength (λ) of X-rays

↓
Bragg's equation

② Interplaner angles between planes and angle of reflection (θ)

$$n\lambda = 2d \sin \theta$$

n → no. of incident x-rays

λ → wavelength of x-ray

d → distance of plane inside the crystal

θ → angle w.r.t plane on incident

Angle w.r.t to
plane

